## **PS7**

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### Binary response model Random effects probit (xtprobit)

Probit case: Assume  $y_{it}^* = x'_{it}\beta + \varepsilon_{it}$ 

Assuming  $\varepsilon_{it} \sim \mathcal{N}(0,1)$  i.i.d we get the usual probit model that can be estimated by MLE.

If we have a one factor error,  $\varepsilon_{it}$ , we have:  $\varepsilon_{it} = \alpha_i + \nu_{it}$ 

To find a MLE, we need to make some extra assumptions on the disturbances, that will give us the random effects probit model:

- 1.  $y_{it}^* = x_{it}^{\prime}\beta + \varepsilon_{it} = x_{it}^{\prime}\beta + \alpha_i + \nu_{it}$  with  $y_{it} = 1_{y_{it}^* > 0}$ .
- 2.  $\alpha_i | X \sim \mathcal{N}(0, \sigma_\alpha^2)$  i.i.d over *i*.
- 3.  $\nu_{it}|X, \alpha_i \sim \mathcal{N}(0, 1)$  i.i.d over *i* and *t*.

**<u>Rk.</u>** <u>1</u> Assumptions 2 and 3 imply that the correlation between two disturbances of the same individual is constant over time. This is sometimes called an equi-correlation assumption. Assumption 2 is the **random effects** assumption. It states that the distribution of  $\alpha_i$  conditional on X does not depend on X.

**<u>Rk.</u>** 2 Here the panel data is balanced. So we can write:  $E(\varepsilon \varepsilon'|X) = I_n \otimes \Omega$ 

where  $\Omega_{T \times T} = (1 + \sigma_{\alpha}^2) \cdot \begin{pmatrix} 1 & \rho & \dots \\ & \ddots & \\ \dots & \rho & 1 \end{pmatrix}$ , with  $\rho = \frac{\sigma_{\alpha}^2}{1 + \sigma_{\alpha}^2}$ .

Then,  $P(y_{it} = 1 | X, \alpha_i) = \Phi(x'_{it}\beta + \alpha_i)$  by A1 and A3. Thus,  $P(y_{it} = 1 | x_{it}) = \int \Phi(x'_{it}\beta + \alpha) f_{\alpha|x_{it}}(\alpha) d\alpha$ . Or,  $P(y_{it} = 1|x_{it}) = \int \Phi(x'_{it}\beta + \alpha)f_{\alpha}(\alpha)d\alpha$  by A2. Thus  $P(y_{it} = 1|x_{it}) = \int \Phi(x'_{it}\beta + \alpha)f_{\alpha}(\alpha)d\alpha$  by A2. **<u>However</u>**, in general,  $P(y_{i1}, ..., y_{iT} | X_i) \neq \prod_t P(y_{it} | x_{it})$ As conditional on  $X_i$ , the random part of the  $y_{it}$ s are the  $\varepsilon_{it} = \alpha_i + \nu_{it}$  which share the same  $\alpha_i$ .

Hence we have to apply the same argument to the likelihood of all the observations of an individual, *i*:  $P(y_{i1}, \dots, y_{iT}|x_i, \alpha_i) = P(y_i|x_i, \alpha_i) = \prod_t P(y_{it}|x_i, \alpha_i) = \prod_t P(y_{it}|x_{it}, \alpha_i)$  by

So, 
$$P(y_i|x_i) = \int \prod_t P(y_{it}|x_i, \alpha) f_{\alpha|x_i}(\alpha) d\alpha = \int \prod_t P(y_{it}|x_i, \alpha) f_{\alpha}(\alpha) d\alpha$$
 by

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A2. And,  $P(y_i|x_i) = \int \prod_t P(y_{it}|x_{it}, \alpha) \frac{1}{\sigma_\alpha} \varphi(\frac{\alpha}{\sigma_\alpha}) d\alpha$  by A2. Note that by A3, we have:  $P(y_{it}|x_{it}, \alpha) = \Phi(x'_{it}\beta + \alpha)^{y_{it}} (1 - \Phi(x'_{it}\beta + \alpha))^{1-y_{it}}$ Thus, we obtain the likelihood for the full sample:  $L(y_1, ..., y_n | x_1, ..., x_n) = \prod_i P(y_i | x_i)$  by A2 and A3.  $L(y_1, ..., y_n | x_1, ..., x_n) = \prod_i \int \prod_t P(y_{it} | x_{it}, \alpha) \frac{1}{\sigma_\alpha} \varphi(\frac{\alpha}{\sigma_\alpha}) d\alpha$ 

Under the assumptions of the random effects probit (one factor model), this is a parametric and fully efficient estimator. We obtain estimators of  $\beta$  and  $\sigma_{\alpha}$ . The estimator  $\hat{\sigma}_{\alpha}$  can be used to test the presence of individual specific effects,  $\alpha_i$ , under the random effects assumption.

#### Extension to ARMA errors

Now we assume:

- 1.  $y_{it}^* = x_{it}'\beta + \varepsilon_{it} = x_{it}'\beta + \alpha_i + \nu_{it}$  with  $y_{it} = 1_{y_{it}^* > 0}$ .
- 2.  $\alpha_i | X \sim \mathcal{N}(0, \sigma_{\alpha}^2)$  i.i.d over *i*.
- 3.  $\nu_{it}|X, \alpha_i \sim ARMA(p,q).$

 $\nu_{it}|X, \alpha_i \sim ARMA(p,q) \text{ means that:}$   $\nu_{it} = \sum_p \alpha_p . \nu_{it-p} + \sum_q \gamma_q . \zeta_{it-q} \text{ where } \zeta_{it} \text{ are iid over } i \text{ and } t.$  We get a general likelihood:  $\int_{a} \int_{a} \int_{bit} \int_{a} \int_{$ 

$$L = \prod_{i=1}^{n} (\underbrace{\int \dots \int_{a_{it}}^{b_{it}} \dots \int}_{T_{i} \text{ integrals}} f_{\varepsilon_{T_i}}(\varepsilon_{i1}, \dots, \varepsilon_{iT_i}).d\varepsilon_{T_i})$$

where if  $y_{it} = 1$  then  $a_{it} = -x'_{it}\beta$  and  $b_{it} = +\infty$ . while if  $y_{it} = 0$  then  $b_{it} = -x'_{it}\beta$  and  $a_{it} = -\infty$ .

The integral does not simplify in this case because of the temporal relationship between the transitory shocks  $\nu_{it}$ . We have to use simulation based methods.

We can used SML, simulated maximum likelihood:

- 1. The parameters of interest are  $\theta_{(K+p+q+1)\times 1} = (\beta', \nu', \gamma', \sigma_{\alpha})'$ .
- 2. We maximize  $\tilde{L}(\theta, R) = 1/n \sum_{i=1}^{n} ln(\tilde{l}(y_i, \theta, R))$  where R is the number of simulations and  $\tilde{l}$  the simulated likelihood.
- 3. We first draw  $R, T \times 1$  uniform random vectors  $\tilde{u}_r$ . We will keep fixed these vectors in all the following process.
- 4. Let  $\theta^{(k)}$  be the value of the parameters at iteration k. To obtain  $\tilde{L}$  we proceed as follows:

- From our assumptions about the pdf of  $\varepsilon$  and our parameters' values,  $\theta^{(k)}$ , we get the simulated disturbances:  $\tilde{\varepsilon}_{i,r}^{(n)} = F_{\varepsilon_i}^{-1}(\tilde{u}_r, \theta^{(n)})$ . This gives us:  $\tilde{y}_{i,r}^{*(n)}$  and  $\tilde{y}_{i,r}^{(n)}$ .
- Using the R simulations we get:  $\tilde{l}(y_i, \theta^{(n)}, R)$  for each *i* and we compute  $\tilde{L}(\theta^{(n)}, R)$ .
- 5. We iterate step 4 among the possible values of  $\theta$  to maximize the simulated log-likelihood.

#### Random effects tobit

We assume:  

$$y_{it}^* = x'_{it}\beta + \varepsilon_{it} = x'_{it}\beta + \alpha_i + \nu_{it}$$

$$y_{it} = 1_{y_{it}^* > 0} * y_{it}^*$$

By the same arguments as before we have:  $f(y_i|X_i) = \int f(y_i|X_i, \alpha) \cdot f_\alpha(\alpha|X_i) d\alpha$ Assuming  $\alpha_i | X \sim \mathcal{N}(0, \sigma_\alpha^2)$  i.i.d over *i*, this becomes:  $f(y_i|X_i) = \int f(y_i|X_i, \alpha) \cdot \frac{1}{\sigma_\alpha} \varphi(\frac{\alpha}{\sigma_\alpha}) d\alpha$ Assuming  $\nu_{it} | X, \alpha_i \sim \mathcal{N}(0, \sigma_\nu^2)$  i.i.d over *i* and *t*, we get:  $f(y_i|X_i) = \int \prod_t f(y_{it}|x_{it}, \alpha) \cdot \frac{1}{\sigma_\alpha} \varphi(\frac{\alpha}{\sigma_\alpha}) d\alpha$ 

• If 
$$y_{it} = 0$$
 then  $f(y_{it}|x_{it}, \alpha) = \Phi(\frac{-x'_{it}\beta - \alpha}{\sigma_{\nu}})$ 

• If 
$$y_{it} > 0$$
 then  $f(y_{it}|x_{it}, \alpha) = \frac{1}{\sigma_{\nu}}\varphi(\frac{y_{it}-x'_{it}\beta-\alpha}{\sigma_{\nu}})$ 

By independence of the observations over the individuals i we get the likelihood as:

$$L = \prod_{i=1}^{n} f(y_i | X_i) = \prod_{i=1}^{n} \left[ \int \prod_{t} f(y_{it} | x_{it}, \alpha) \cdot \frac{1}{\sigma_{\alpha}} \varphi(\frac{\alpha}{\sigma_{\alpha}}) d\alpha \right].$$